

Search Notes

Application/Control No.

10/816,622

Examiner

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Applicant(s)/Patent under
Reexamination

OOTSU ET AL.

Art Unit

1765

SEARCHED

Class	Subclass	Date	Examiner
216	11	2/13/2006	BT
216	24	2/13/2006	BT
216	96	2/13/2006	BT

INTERFERENCE SEARCHED

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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Search inventors' names and keyword using USPAT, USPG-PUB, JPO, EPO, DERWENT database	2/13/2006	BT